

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	5	netlist same node same (DRC or (design adj rule adj check\$3)) and (rule same (plurality or multiple or few))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:28
S2	0	netlist same node same (DRC or (design adj rule adj check\$3)) and (rule same (plurality or multiple or few)) and extract\$3 and (neighbor\$3 near3 node)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:30
S3	0	netlist same node same (DRC or (design adj rule adj check\$3)) and (rule same (plurality or multiple or few)) and extract\$3 and neighbor\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:30
S4	4	netlist same node same (DRC or (design adj rule adj check\$3)) and (rule same (plurality or multiple or few)) and extract\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:44
S5	6	netlist same node same (DRC or (design adj rule adj check\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 17:53
S6	169	netlist and node and (DRC or (design adj rule adj check\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 15:31
S7	30	netlist and node and (DRC or (design adj rule adj check\$3)) and extract\$3 and neighbor\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 13:48
S8	3	netlist and (node same (DRC or (design near3 rule near3 check\$3))) and extract\$3 and neighbor\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 14:08
S9	3	netlist and (node same (DRC or (design near3 rule near3 check\$3))) and (extract\$3 or select\$3 or determin\$3 or identif\$3 or defin\$3) and neighbor\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 14:11
S10	0	netlist and (node same (DRC or (design near3 rule near3 check\$3))) and (new near3 rule) and neighbor\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 14:12

S11	0	netlist and (node same (DRC or (design near3 rule near3 check\$3)) same neighbor\$3) and ((new or add\$3) near3 rule)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 14:12
S12	2	netlist and (node same (DRC or (design near3 rule near3 check\$3)) same neighbor\$3) and ((new or add\$3) samerule)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 14:12
S13	2	netlist and (node same (DRC or (design near3 rule near3 check\$3)) same neighbor\$3) and ((new or add\$3) same rule)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 14:14
S14	2	netlist and (node same (DRC or (design near3 rule near3 check\$3)) same neighbor\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 14:15
S15	3	netlist and (node same (DRC or (design near3 rule near3 check\$3))) and (rule same neighbor\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 14:16
S16	3	netlist and (node same (DRC or (design near3 rule near3 check\$3))) and (rule same neighbor\$3 same node)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 14:17
S17	3	netlist and (DRC or (design near3 rule near3 check\$3)) and (rule same neighbor\$3 same node)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 14:19
S18	4	(DRC or (design near3 rule near3 check\$3)) and (rule same neighbor\$3 same node)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 14:24
S19	17	(DRC or (design near3 rule near3 check\$3)) and (extract\$3 near5 node)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 15:31
S20	44	netlist and node and (DRC or (design adj rule adj check\$3)) and (neighbor\$3 or adjust\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 16:06

S21	11	netlist and ((node or property) same extract\$3) and ((DRC or (design adj rule adj check\$3)) same (modif\$3 or add\$3 or chang\$3) same (rule or constraint))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 16:36
S22	0	(netlist and (node or property) and (DRC or (design adj rule adj check\$3)) and extract*).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 16:38
S23	2	(netlist and (node or property) and (DRC or (design adj rule adj check\$3)) and extract\$3).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 16:47
S24	12	netlist and (node or property) and (DRC or (design adj rule adj check\$3)) and extract\$3 and (rule near3 basic)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 16:54
S25	0	node same (DRC or (design adj rule adj check\$3)) and netlist and sub-rule	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 17:55
S26	0	node same (DRC or (design adj rule adj check\$3)) and netlist and (sub adj rule)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 18:22
S27	27	(DRC or (design adj rule adj check\$3)) near5 netlist	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 18:23
S28	27	((DRC or (design adj rule adj check\$3)) near5 netlist) and (extract\$3 or select\$3 or defin\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/26 18:24
S29	5	((DRC or (design adj rule adj check\$3)) near5 netlist) same (extract\$3 or select\$3 or defin\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/27 07:17
S30	3	((DRC or (design adj rule adj check\$3)) near5 netlist) same extract\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/27 07:24

S31	25	(DRC or (design adj rule adj check\$3)) same (netlist near3 extract\$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/27 07:52
S32	81	(DRC or (design adj rule adj check\$3)) and (netlist near3 extract\$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/27 07:53
S33	0	(DRC or (design adj rule adj check\$3)) and (netlist near3 extract\$) and knowledg\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/27 07:53
S34	17	(DRC or (design adj rule adj check\$3)) and (netlist near3 extract\$) and knowledg\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/27 08:45
S35	18	(DRC or (design adj rule adj check\$3)) and ((netlist near3 extract\$) same hierarch\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/27 08:46



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IEEE CNF	IEEE Conference Proceeding
IEE CNF	IEE Conference Proceeding
IEEE STD	IEEE Standard

- ☐ 1. **Developing a distributed architecture for design rule checkin**
Pais, A.P.V.; Anido, M.L.; Oliveira, C.E.T.;
Circuits and Systems, 2001. MWSCAS 2001. Proceedings of the
2001 Midwest Symposium on
Volume 2, 14-17 Aug. 2001 Page(s):678 - 681 vol.2
Digital Object Identifier 10.1109/MWSCAS.2001.986279
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» Key

IEEE JNL IEEE Journal or Magazine

IEEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

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- ☐ 1. **PALACE: A parallel and hierarchical layout analyzer and circuit**
Scherber, F.; Barke, E.; Meier, W.;
European Design and Test Conference, 1996. ED&TC 96. Proceedings
11-14 March 1996 Page(s):357 - 361
Digital Object Identifier 10.1109/EDTC.1996.494325
[AbstractPlus](#) | Full Text: [PDF](#)(464 KB) IEEE CNF
- ☐ 2. **Hierarchical layout verification for submicron designs**
Meier, W.;
Design Automation Conference, 1990. EDAC. Proceedings of the
12-15 March 1990 Page(s):382 - 386
Digital Object Identifier 10.1109/EDAC.1990.136677
[AbstractPlus](#) | Full Text: [PDF](#)(476 KB) IEEE CNF
- ☐ 3. **Performance analysis of an IC-mask design rule check and n**
software suite
Thomas, P.R.; Brown, A.D.;
Circuits, Devices and Systems, IEE Proceedings G
Volume 136, Issue 4, Aug 1989 Page(s):205 - 214
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